

Notice of References Cited	Application/Control No. 09/820,054	Applicant(s)/Patent Under Reexamination SCHRAN ET AL.	
	Examiner Etienne P LeRoux	Art Unit 2161	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0019941	02-2002	CHAN et al.	713/185
*	B	US-2002/0078191	06-2002	Lorenz, Todd	709/223
*	C	US-6,006,334	12-1999	Nguyen et al.	726/5
*	D	US-6,651,217	11-2003	Kennedy et al.	715/507
*	E	US-6,237,033	05-2001	Doeberl et al.	709/223
*	F	US-6,286,001	09-2001	Walker et al.	707/9
*	G	US-6,851,060	02-2005	Shrader, Theodore Jack London	726/10
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.